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March 2013

FQP17P10 P-Channel QFET® MOSFET

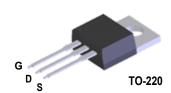
- 100 V, - 16.5 A, 190 $m\Omega$

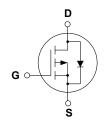
Description

This P-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

Features

- -16.5 A, -100 V, $R_{DS(on)}$ = 190 m Ω (Max.) @V_{GS} = -10 V, I_D = 8.25 A
- Low Gate Charge (Typ. 30 nC)
- Low Crss (Typ. 100 pF)
- · 100% Avalanche Tested
- 175°C Maximum Junction Temperature Rating





Absolute Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter			FQP17P10	Unit
V _{DSS}	Drain-Source Voltage		-100	V	
I _D	Drain Current	- Continuous (T _C = 25°C)		-16.5	Α
		- Continuous (T _C = 10	0°C)	-11.7	Α
I_{DM}	Drain Current	- Pulsed	(Note 1)	-66	Α
V_{GSS}	Gate-Source Vo	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy		(Note 2)	580	mJ
I _{AR}	Avalanche Current		(Note 1)	-16.5	А
E _{AR}	Repetitive Avalanche Energy		(Note 1)	10	mJ
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	-6.0	V/ns
P _D	Power Dissipation (T _C = 25°C)			100	W
	- Derate above 25°C			0.67	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to +175	°C
Tı	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds			300	°C
-					

Thermal Characteristics

Symbol	Parameter	FQP17P10	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	1.5	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink, Typ.	0.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-100			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = -250 μA, Referenced to 25°C		-0.1		V/°C
I _{DSS}	7 0 1 1/1 5 1 0 1	V _{DS} = -100 V, V _{GS} = 0 V			-1	μА
	Zero Gate Voltage Drain Current	V _{DS} = -80 V, T _C = 150°C			-10	μА
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = -30 V, V _{DS} = 0 V			-100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = -250 μA	-2.0		-4.0	V
R _{DS(on)}	Static Drain-Source $V_{GS} = -10 \text{ V}, I_D = -8.25 \text{ A}$			0.14	0.19	Ω
9 _{FS}	Forward Transconductance $V_{DS} = -40 \text{ V}, I_D = -8.25 \text{ A}$			9.9		S
Dynam	ic Characteristics					
C _{iss}	Input Capacitance	V _{DS} = -25 V, V _{GS} = 0 V,		850	1100	pF
Coss	Output Capacitance	f = 1.0 MHz		310	400	pF
C _{rss}	Reverse Transfer Capacitance			100	130	pF
Switchi	ing Characteristics					
t _{d(on)}	Turn-On Delay Time			17	45	ns
t _r	Turn-On Rise Time	$V_{DD} = -50 \text{ V}, I_{D} = -16.5 \text{ A},$ $R_{G} = 25 \Omega$		200	410	ns
t _{d(off)}	Turn-Off Delay Time	11G - 20 sz		45	100	ns
t _f	Turn-Off Fall Time	(Note 4)		100	210	ns
Qg	Total Gate Charge	V _{DS} = -80 V, I _D = -16.5 A,		30	39	nC
Q _{gs}	Gate-Source Charge	V _{GS} = -10 V		4.8		nC
Q _{gd}	Sate-Drain Charge (Note 4)			17		nC
Drain-S	Source Diode Characteristics ar	nd Maximum Ratings				
Is	Maximum Continuous Drain-Source Dic			-16.5	Α	
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				-66	Α
V _{SD}	Drain-Source Diode Forward Voltage V _{GS} = 0 V, I _S = -16.5 A				-4.0	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = -16.5 \text{ A},$		120		ns
Q _{rr}	Reverse Recovery Charge $dI_F / dt = 100 \text{ A}/\mu\text{s}$			0.52		μС

Notes:
1. Repetitive Rating : Pulse width limited by maximum junction temperature
2. L = 3.2mH, I_{AS} = -16.5A, V_{DD} = -25V, R_G = 25 Ω , Starting T_J = 25°C
3. I_{SD} \leq -16.5A, di/dt \leq 300A/µs, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C
4. Essentially independent of operating temperature

Typical Characteristics

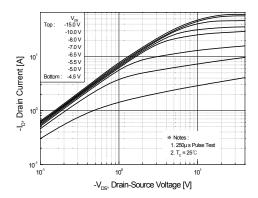


Figure 1. On-Region Characteristics

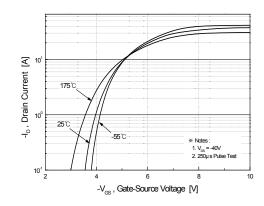


Figure 2. Transfer Characteristics

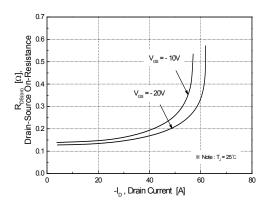


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

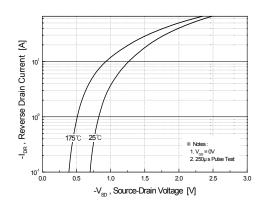


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

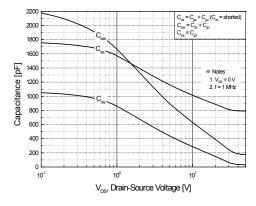


Figure 5. Capacitance Characteristics

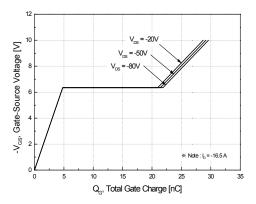
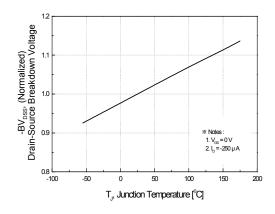


Figure 6. Gate Charge Characteristics

Dimensions in Millimeters

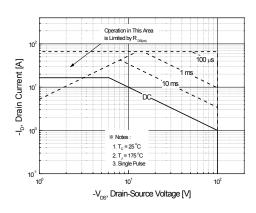
Typical Characteristics (Continued)



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Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



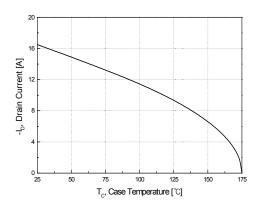


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

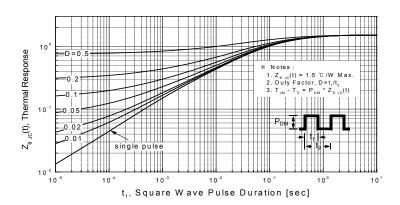
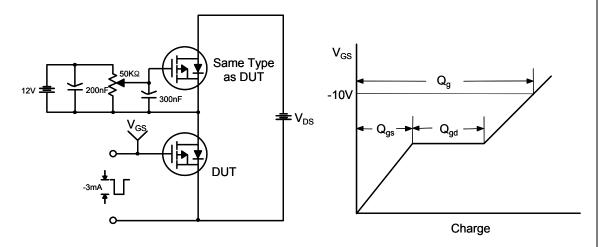
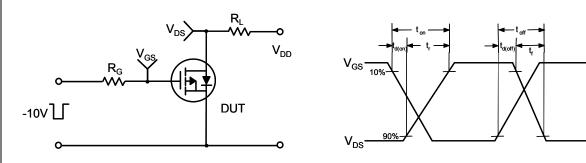


Figure 11. Transient Thermal Response Curve

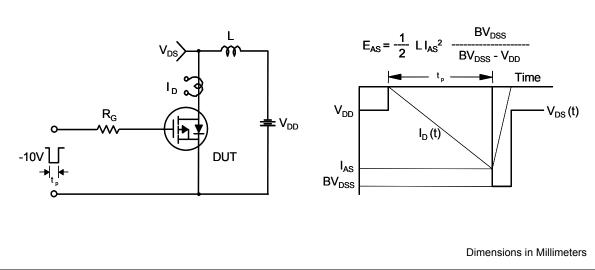
Gate Charge Test Circuit & Waveform



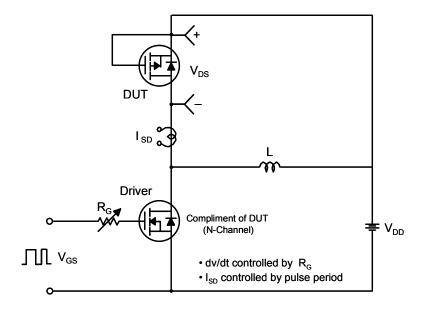
Resistive Switching Test Circuit & Waveforms

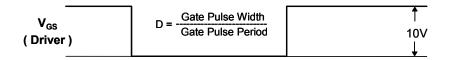


Unclamped Inductive Switching Test Circuit & Waveforms

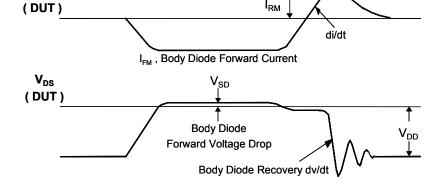


Peak Diode Recovery dv/dt Test Circuit & Waveforms

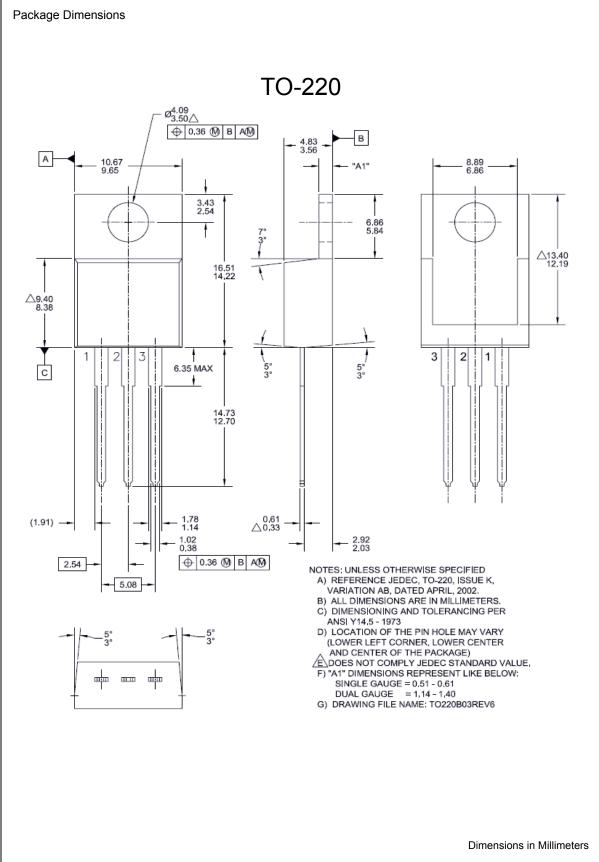




Body Diode Reverse Current



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